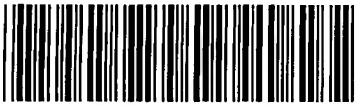


Search Notes

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Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
Updated	previous serach	9/6/2007	TMB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR